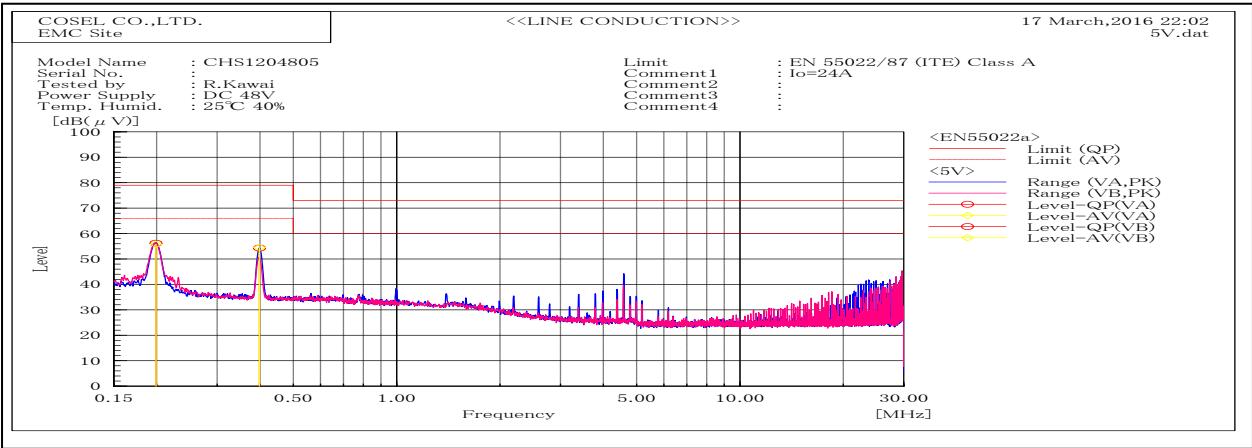
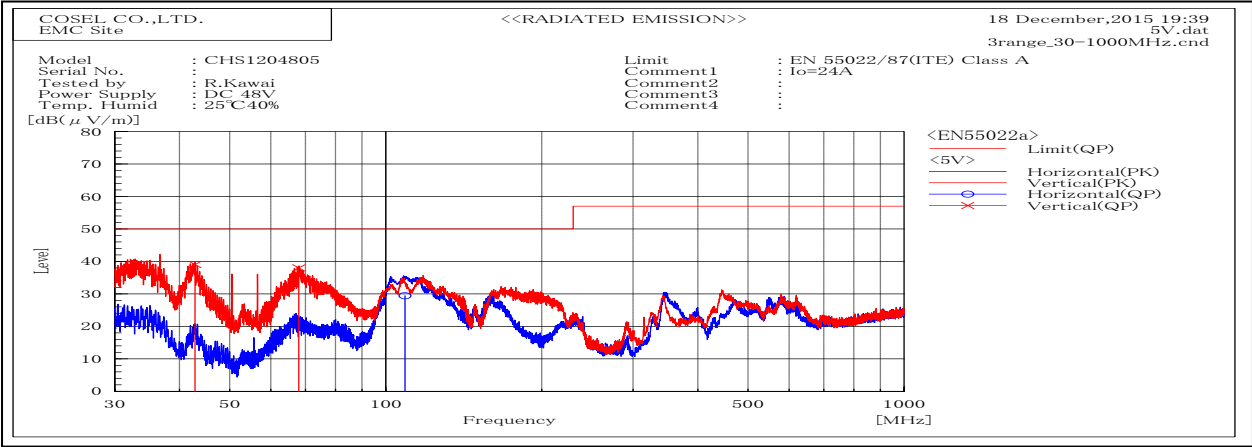


DATA SHEET		Date	06-May-16
Model	CHS1204805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



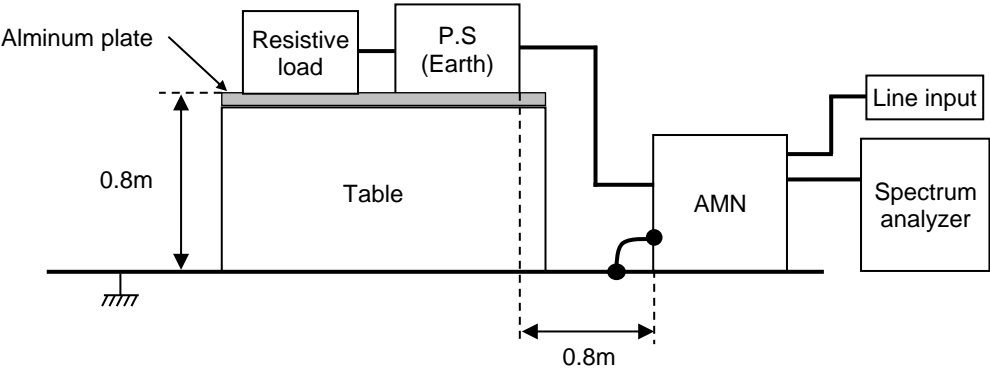
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.199		VB	36.1	35.9	20.1	56.2	56.1	79.0	66.0	22.8	9.9	Pass	
0.398		VA	34.3	34.2	20.0	54.3	54.1	79.0	66.0	24.7	11.9	Pass	



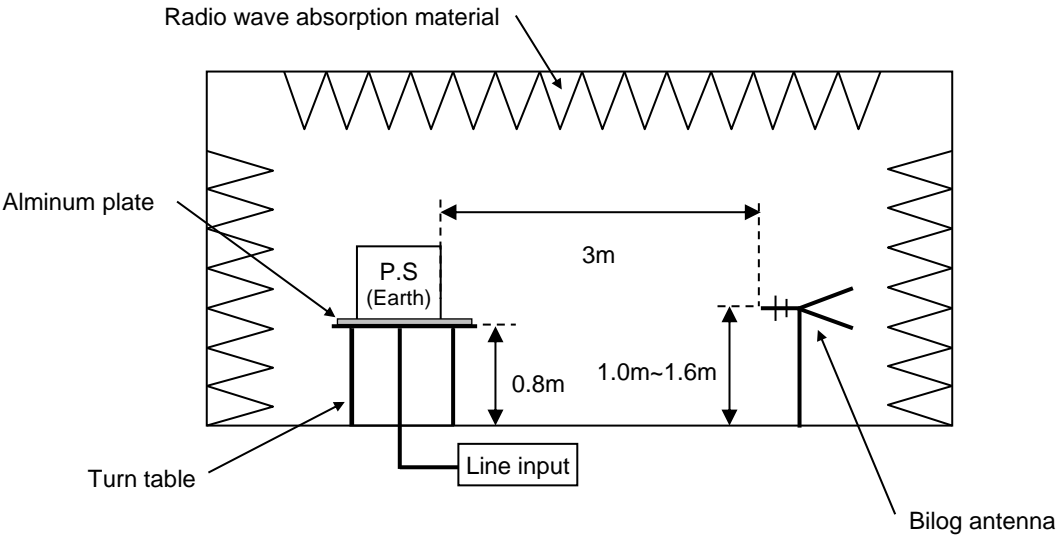
Frequency MHz	Harm	Polarization	Stability	Reading dB(μV)		Factor dB(1/m)	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
				QP	AV		QP	AV						
42.858		V	Stable	56.0		-17.0	39.0		50.0	11.0	Pass	110.0	36.0	
67.942		V	Stable	59.0		-21.0	38.0		50.0	12.0	Pass	109.0	285.0	
108.946		H	Stable	49.6		-20.2	29.4		50.0	20.6	Pass	135.0	310.0	

DATA SHEET		Date	06-May-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

1. Line conduction



2. Radiated emission



Conditions

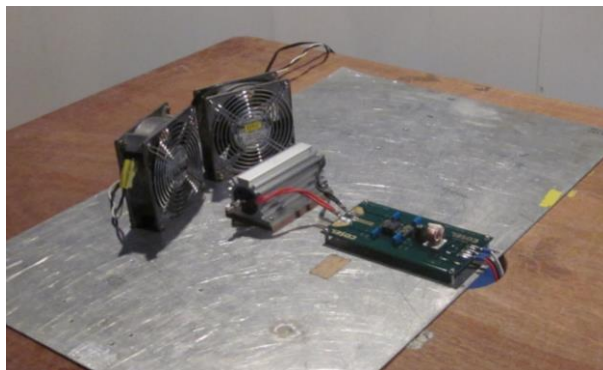
Test : EMI
Model Name : CHS12048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

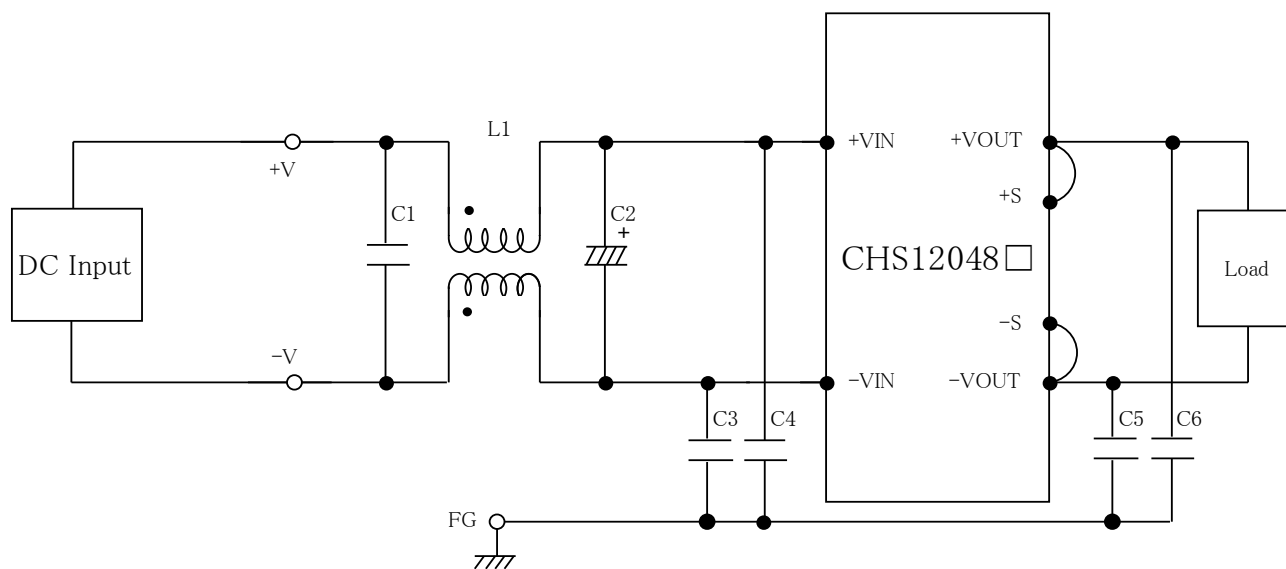


Fig.1 Testing circuitry

L1 : 1mH SC-05-10J (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2 : 100V 47 μ F PWseries (nichicon)
C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)